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August 2014

FDPF33N25T

N-Channel UniFETTM MOSFET 250 V, 33 A, 94 m Ω

Features

- $R_{DS(on)}$ = 94 m Ω (Max.) @ V_{GS} = 10 V, I_D = 16.5 A
- Low Gate Charge (Typ. 36.8 nC)
- Low C_{rss} (Typ. 39 pF)
- 100% Avalanche Tested

Applications

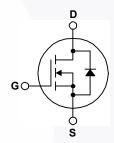
- PDP TV
- Lighting
- · Uninterruptible Power Supply
- · AC-DC Power Supply

Description

UniFETTM MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.







Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		FDPF33N25T FDPF33N25TRDTU	Unit	
V _{DSS}	Drain-Source Voltage	Drain-Source Voltage		V
I _D	Drain Current	- Continuous (T _C = 25°C) - Continuous (T _C = 100°C)	33* 20.4*	A A
I _{DM}	Drain Current	- Pulsed (Note 1)	132*	Α
V_{GSS}	Gate-Source voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		918	mJ
I _{AR}	Avalanche Current (Note 1)		33	Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		23.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Not		4.5	V/ns
P _D	Power Dissipation	(T _C = 25°C) - Derate Above 25°C	37 0.29	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C

^{*}Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FDPF33N25T FDPF33N25TRDTU	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	3.4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	C/VV

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDPF33N25T	FDPF33N25T	TO-220F	Tube	N/A	N/A	50 units
FDPF33N25TRDTU	FDPF33N25T	TO-220F (LG-formed)	Tube	N/A	N/A	50 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics			•		
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A, } T_J = 25^{\circ}\text{C}$				V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.25		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 250 V, V _{GS} = 0 V V _{DS} = 200 V, T _C = 125°C			1 10	μA μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charac	teristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 16.5 A		0.077	0.094	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 16.5 A		26.6		S
Dynamic C	Characteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		1640	2135	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		330	430	pF
C _{rss}	Reverse Transfer Capacitance			39	59	pF
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time	V_{DD} = 125 V, I_{D} = 33 A, V_{GS} = 10 V, R_{G} = 25 Ω		35	80	ns
t _r	Turn-On Rise Time			230	470	ns
t _{d(off)}	Turn-Off Delay Time			75	160	ns
t _f	Turn-Off Fall Time	(Note 4)		120	250	ns
Qg	Total Gate Charge	$V_{DS} = 200 \text{ V}, I_{D} = 33 \text{ A},$		36.8	48	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 10 V (Note 4)		10		nC
Q_{gd}	Gate-Drain Charge			17		nC
Drain-Sou	rce Diode Characteristics and Maximun	n Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				33	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				132	Α
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 33 A			1.4	٧
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 33 \text{ A,}$ $dI_F/dt = 100 \text{ A/}\mu\text{s}$		220		ns
Q _{rr}	Reverse Recovery Charge			1.71		μС

Notes

^{1.} Repetitive rating: pulse-width limited by maximum junction temperature.

^{2.} L = 1.35 mH, I_{AS} = 33 A, V_{DD} = 50 V, R_{G} = 25 Ω , starting T_{J} = 25°C.

^{3.} I $_{SD} \leq$ 33 A, di/dt \leq 200 A/µs, V $_{DD} \leq$ BV $_{DSS},$ starting T $_{J}$ = 25°C.

^{4.} Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

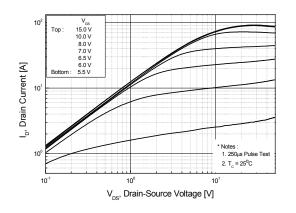


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

Figure 2. Transfer Characteristics

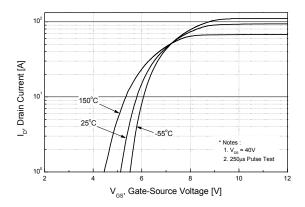


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

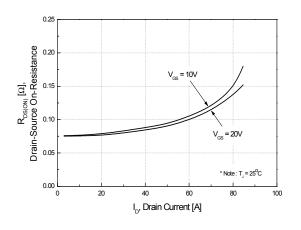


Figure 5. Capacitance Characteristics

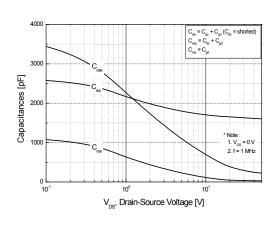
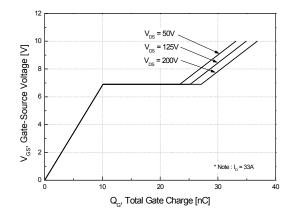


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

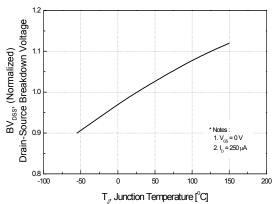


Figure 9. Maximum Safe Operating Area

Figure 8. On-Resistance Variation vs. Temperature

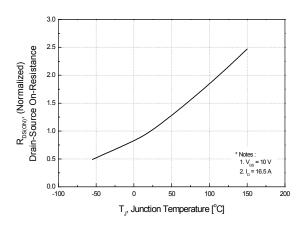
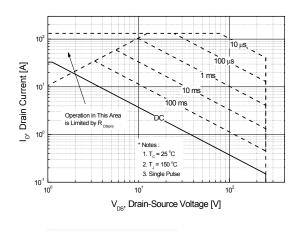


Figure 10. Maximum Drain Current vs. Case Temperature



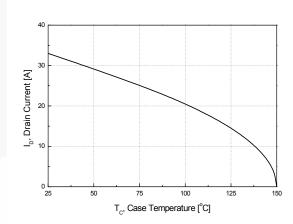
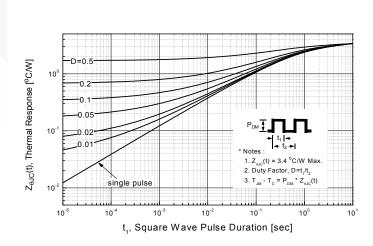


Figure 11. Transient Thermal Response Curve



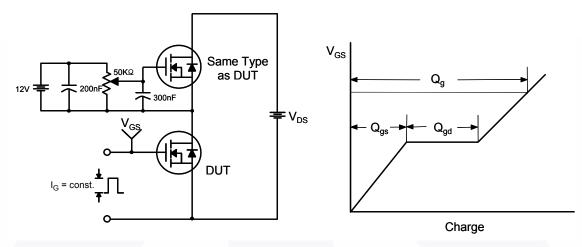


Figure 12. Gate Charge Test Circuit & Waveform

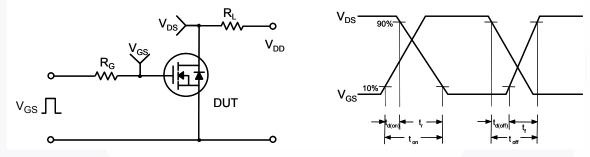


Figure 13. Resistive Switching Test Circuit & Waveforms

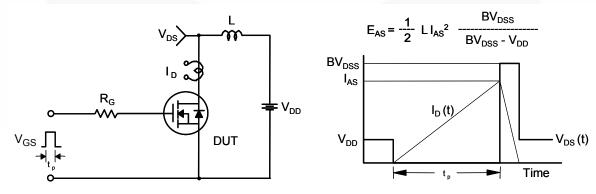


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

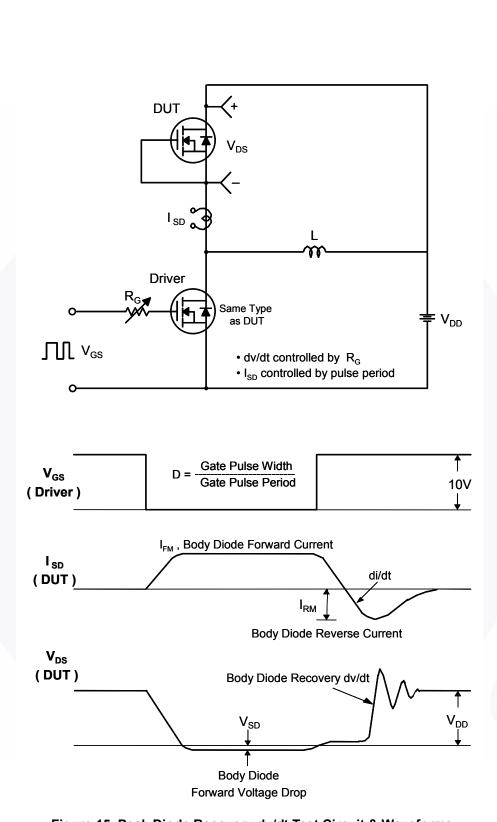
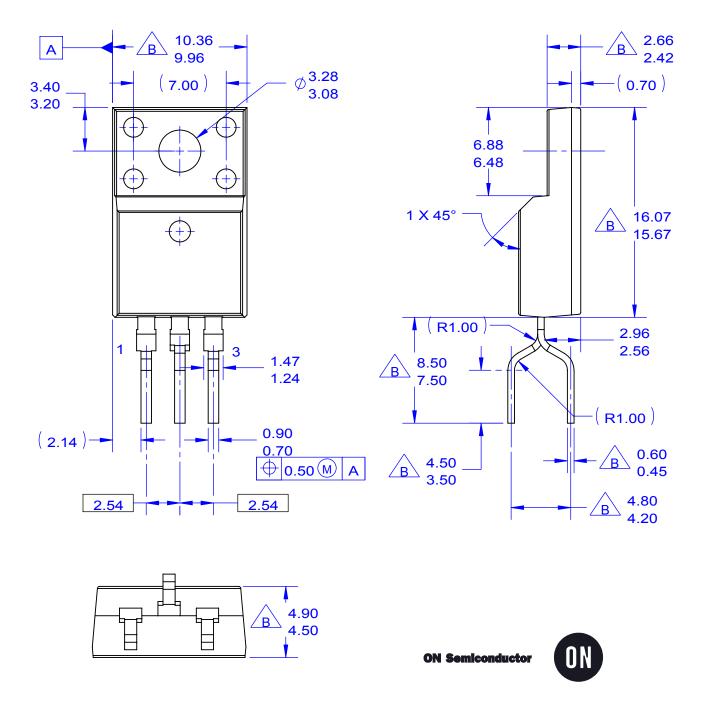


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

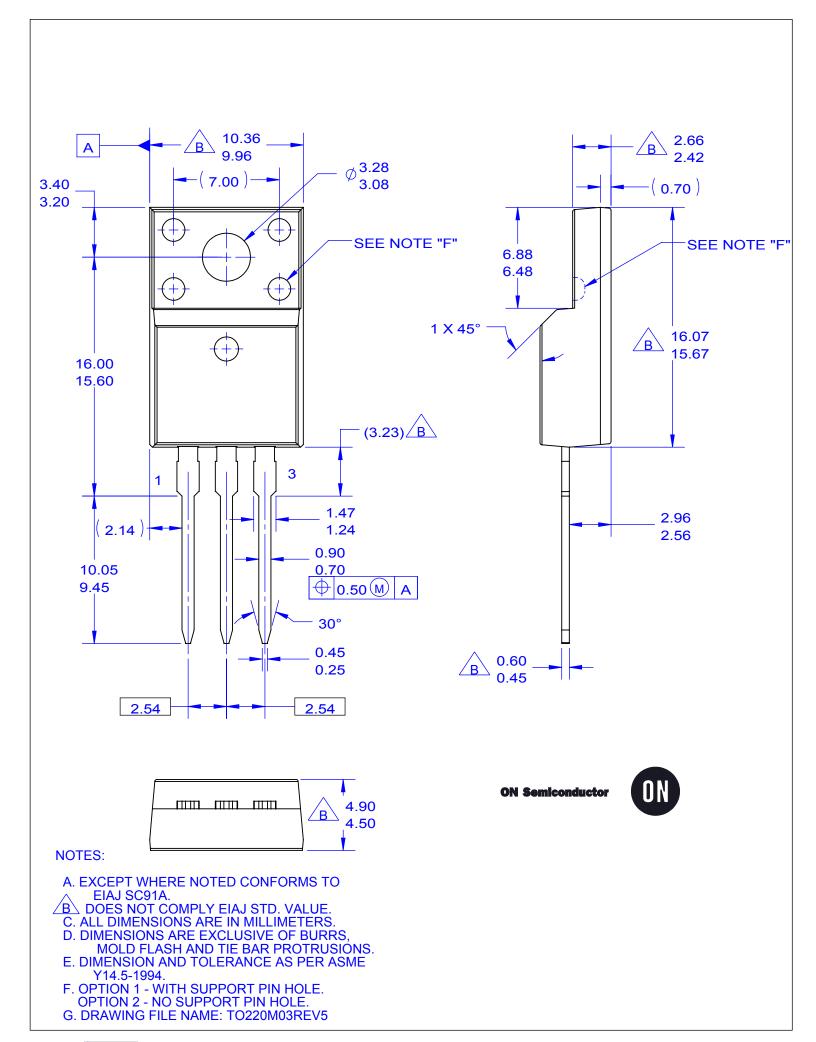


NOTES:

- A. EXCEPT WHERE NOTED CONFORMS TO
- EIAJ SC91A.

 B DOES NOT COMPLY EIAJ STD. VALUE.
 C. ALL DIMENSIONS ARE IN MILLIMETERS.

 - D. DIMENSIONS ARE EXCLUSIVE OF BURRS
 - MOLD FLASH AND TIE BAR PROTRUSIONS. E. DIMENSION AND TOLERANCE AS PER ASME Y14.5-1994.
 - F. DRAWING FILE NAME: TO220N03REV2



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